ESCC

DOCUMENT CHANGE REQUEST

DCR number	687	Changes required for: N/A	Originator: Benoit Cornanguer
Date: 2011/12/06		Date sent: 2011/10/26	Organisation: STMicroelectronics
Status: IMPLEMENTED			

Title:	TRANSISTORS, POWER, MOSFET, P-CHANNEL, RAD-HARD BASED ON TYPE STRH40P10

Number:	5205/025	Issue:	1

Other documents affected:

Page:

Pages 10 & 11

Paragraph:

2.5.1 Room Temperature Electrical Measurements

Original wording:

The limits of the AC test parameters [td(on)/tr/tf] need to be updated as defined below:
td(on): minimum limit=15ns instead of 15.5ns
td(on): maximum limit=33ns instead of 23.4ns
tr: minimum limit=19ns instead of 19.6ns
tr: maximum limit=43ns instead of 29.4ns
tf: minimum limit=34ns instead of 37ns

The test conditions of the reverse recovery time (trr) need to be updated:
di/dt=40A/µs instead of 100A/µs.

Proposed wording:

Justification:

The ESCC detail specification has been written from the characterization results.
All AC electrical test parameters during the characterization phase have been done near of the body of the TO-254AA package.
Unlike for the ESCC qualification we have used a test socket; in this case we lost performance for the switching times due to that the measurements are done more far of the body of the package.
If we take into account this statement, we are sure to cover all customer applications by giving to them the worst limits. This is not the case if we keep the limits defined after the characterization.
About the test conditions of the trr, this is a wrong information given initially.

Attachments:
N/A
Modifications:
N/A
Approval signature:
Date signed:
2011-12-06